

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/938,815	KWON, YOUNG-SIG
	Examiner	Art Unit
	TAN X. DINH	2627

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Interference Search History Printout		6/9/2006	T.D.